

SEMICELL CAL-DIODE

SKCD 121 C 060 I3

I_F = 210 A

V_{RRM} = 600 V

Size: 11 mm X 11 mm

Package: wafer frame

Features

- 600V, 1200V and 1700V
- low forward voltage drop
- easy paralleling due to a small forward voltage spread
- low temperature dependence
- very soft recovery behavior
- small switching losses
- high ruggedness
- compatible to thick wire bonding
- compatible to all standard solder processes

Typical Applications

- freewheeling diode for IGBT
- optimal at frequencies > 8 kHz

Absolute Maximum Ratings

Symbol	Conditions	Values	Units
V _{RRM}	T _{vj} = 25 °C, I _R = 0,5 mA	600	V
I _{F(AV)}	T _h = 80 °C, T _{vjmax} = 150 °C	160	A
I _{FSM}	T _{vj} = 25 °C, 10 ms, half sine wave		A
	T _{vjmax} = 150 °C, 10 ms, half sine wave	2100	A
T _{vjmax}		+ 150	°C

Electrical Characteristics

Symbol	Conditions	min.	typ.	max.	Units
I ² t	T _{vjmax} , 10 ms, half sine wave		22000		A ² s
I _R	T _{vj} = 25 °C, V _{RRM}		0,5		mA
	T _{vj} = 125 °C, V _{RRM}		10		mA
V _F	T _{vj} = 25 °C, I _F = 245 A	1,35	1,6		V
	T _{vj} = 125 °C, I _F = 245 A	1,35	1,6		V
V _(TO)	T _{vj} = 125 °C	0,9			V
r _T	T _{vj} = 125 °C		1,8		mΩ

Dynamic Characteristics

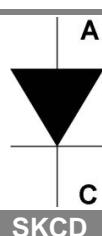
Symbol	Conditions	min.	typ.	max.	Units
t _{rr}	T _{vj} = 25 °C, 200 A ,300 V, 1000 A/μs				ns
	T _{vj} = 125 °C, 200 A ,300 V, 1000 A/μs				ns
Q _{rr}	T _{vj} = 25 °C, 200 A, 300 V, 1000 A/μs	5			μC
	T _{vj} = 125 °C, 200 A, 300 V, 1000 A/μs	10,7			μC
I _{rrm}	T _{vj} = 25 °C, 200 A, 300 V, 1000 A/μs				A
	T _{vj} = 125 °C, 200 A, 300 V, 1000 A/μs	75			A

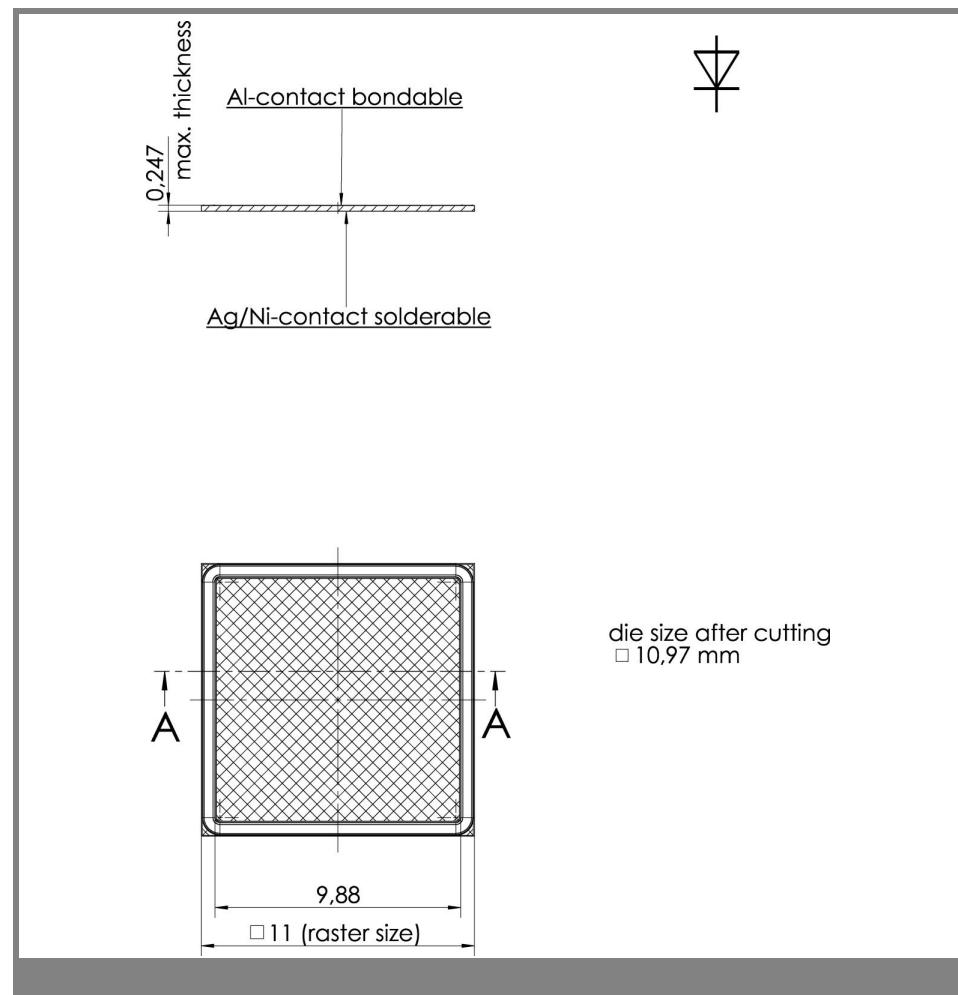
Thermal Characteristics

Symbol	Conditions	min.	typ.	max.	Units
T _{vj}		- 40		+ 150	°C
T _{stg}		- 40		+ 150	°C
T _{solder}	10 min			+ 250	°C
T _{solder}	5 min			+ 320	°C
R _{th(j-h)}	soldered on 0,38 mm DCB, reference point on copper heatsink close to the chip.	0,24			K / W

Mechanical Characteristics

Parameter		Units
raster size	11 x 11	mm
Area total	121	mm ²
Chips / wafer	76	pcs
Anode metallisation	bondable (Al)	
Cathode metallisation	solderable (Ag / Ni)	
wire bond	Al, diameter ≤ 500 μm	





This technical information specifies semiconductor devices. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.